AMENDMENTS TO THE CLAIMS

1. (Canceled)

2. (Currently Amended) A temperature control device used for an electronic device testing apparatus for conducting a test on an electronic device to be tested by sending a test pattern to the electronic device to be tested and detecting a response pattern thereto, comprising:

a temperature adjusting device provided to contact with said electronic device to be tested; and

a power control means for controlling power consumption of said temperature adjusting device, so that total power of a power consumption of said electronic device by said test pattern and a power consumption of said temperature adjusting device becomes a constant value, ~~The temperature control device as set forth in claim 1,~~ wherein said power control means comprises

a power consumption pattern prediction portion for predicting a power consumption pattern in said electronic device to be tested from a test pattern transmitted to said electronic device;

a power consumption canceling pattern generation portion for generating a power consumption canceling pattern for canceling a power consumption pattern in said electronic device to be tested; and

a power consumption canceling pattern transmission portion for sending said power consumption canceling pattern to said temperature adjusting device.

3. (Canceled)

4. (Currently Amended) The temperature control device as set forth in ~~claim 1~~ claim 2, wherein temperature change characteristics by a power consumption of said temperature adjusting device are equal to or close to those by a power consumption of said electronic device to be tested.

5. (Original) The temperature control device as set forth in claim 4, wherein a heat capacity of said temperature adjusting device is equal to or close to that of said electronic device to be tested.

6. (Canceled)

7. (Currently Amended) A temperature control method for conducting a test on an electronic device to be tested by transmitting a test pattern to said electronic device to be tested and detecting a response pattern thereto, comprising the steps of:

bringing a temperature adjusting device to said electronic device to be tested; and

controlling a power consumption of said temperature adjusting device, so that a total power of a power consumption of said electronic device to be tested and a power consumption of said temperature adjusting device becomes a constant value, ~~The temperature control method as set forth in claim 6,~~ wherein said step for controlling the power consumption comprises steps of

predicting a power consumption pattern in said electronic device to be tested from a test pattern transmitted to said electronic device to be tested;

generating a power consumption canceling pattern for canceling a power consumption in said electronic device to be tested; and

transmitting said power consumption canceling pattern to said temperature adjusting device.

8. (Canceled)

9. (Currently Amended) An electronic device testing handler, comprising:

a pusher for pressing an electronic device to be tested against a contact terminal, to which a test pattern is input; and

a temperature adjusting device provided to said pusher so as to contact with said electronic device to be tested; and

a controller for controlling ~~wherein~~ a power consumption of said temperature adjusting device ~~is controlled,~~ so that total power of a power consumption of said electronic device to be tested by said test pattern and a power consumption of said temperature adjusting device becomes a constant value,

wherein said controller comprises:

a power consumption pattern prediction portion for predicting a power consumption pattern in said electronic device to be tested from a test pattern transmitted to said electronic device;

a power consumption canceling pattern generation portion for generating a power consumption canceling pattern for canceling a power consumption pattern in said electronic device to be tested; and

a power consumption canceling pattern transmission portion for sending said power consumption canceling pattern to said temperature adjusting device.

10. (Canceled)

11. (Currently Amended) An electronic device testing apparatus, comprising:

a test pattern generation means for generating a predetermined test pattern;

a test pattern transmission means for transmitting a test pattern generated by said test pattern generation means to a contact terminal, against which a terminal of an electronic device to be tested is pressed;

a determination means for evaluating said electronic device to be tested based on a response pattern to said test pattern; and

a power control means for controlling a power consumption of said temperature adjusting device, so that total power of a power consumption of said electronic device to be tested by said test pattern and a power consumption of a temperature adjusting device provided for contacting with said electronic device to be tested becomes a constant value, ~~The electronic device testing apparatus as set forth in claim 10,~~ wherein said power control means comprises:

a power consumption pattern prediction portion for predicting a power consumption pattern in said electronic device to be tested from a test pattern transmitted to said electronic device to be tested;

a power consumption canceling pattern generation portion for generating a power consumption canceling pattern for canceling a power consumption pattern in said electronic device to be tested; and

a power consumption canceling pattern transmission portion for transmitting said power consumption canceling pattern to said temperature adjusting device.

12. (Canceled)

13. (Currently Amended) An electronic device testing method for conducting a test on an electronic device to be tested by transmitting a predetermined test pattern to said electronic device to be tested via a contact terminal and detecting a response pattern thereto in a state of pressing a terminal of said electronic device to said contact terminal, comprising the steps of:

bringing a temperature adjusting device contact with said electronic device to be tested;

controlling a power consumption of said temperature adjusting device, so that total power of a power consumption of said electronic device to be tested by said test pattern and a power consumption of said temperature adjusting device becomes a constant value; and

evaluating said electronic device to be tested based on a response pattern to said test pattern,

wherein said step for controlling the power consumption comprises steps of:

predicting a power consumption pattern in said electronic device to be tested from a test pattern transmitted to said electronic device to be tested;

generating a power consumption canceling pattern for canceling a power consumption in said electronic device to be tested; and

transmitting said power consumption canceling pattern to said temperature adjusting device.

14.-24. (Canceled)